TOSHIBA 2SC5322FT

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 3 2 2 F T

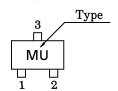
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

Low Noise Figure : NF=1.4dB (f=2GHz): $|S_{21e}|^2 = 10 dB (f = 2GHz)$

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	8	V
Collector-Emitter Voltage	v_{CEO}	5	V
Emitter-Base Voltage	$V_{ m EBO}$	1.5	V
Collector Current	$I_{\mathbf{C}}$	10	mA
Base Current	$I_{\mathbf{B}}$	5	mA
Collector Power Dissipation	PC	100	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	°C

MARKING



0.22 ± 0.05 1.2 ± 0.05 0.8 ± 0.05 0.32 3 1. BASE **EMITTER** TESM COLLECTOR **JEDEC EIAJ TOSHIBA** 2-1B1A

Unit in mm

MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	${f f_T}$	$V_{CE}=3V, I_{C}=7mA$	9	_	_	GHz
		V_{CE} =3V, I_{C} =7mA, f=1GHz	12.5	15.5	_	dB
	$ S_{21e} ^2$ (2)	V_{CE} =3V, I_{C} =7mA, f=2GHz	7	10	_	
Noise Figure —	NF (1)	V_{CE} =3V, I_{C} =3mA, f=1GHz	_	0.9	1.8	dB
	NF (2)	$V_{CE}=3V, I_{C}=3mA, f=2GHz$	_	1.4	2.2	ub

ELECTRICAL CHARACTERISTICS ($Ta = 25^{\circ}C$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB}=1V, I_C=0$	_	_	1	μ A
DC Current Gain	${ m h_{FE}}$	$V_{CE}=3V, I_{C}=7mA$	50	_	250	
Output Capacitance	C_{ob}	$V_{CB} = 2.5V, I_{E} = 0, f = 1MHz$	_	0.4	_	pF
Reverse Transfer Capacitance	$\mathrm{c_{re}}$	(Note)	_	0.3	_	pF

(Note) C_{re} is measured by 3 terminal method with Capacitance bridge. CAUTION

This device electrostatic sensitivity. Please handle with caution.

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